

Mechanical data: $A_x= 450\mu\text{m}$. $A_y=330\mu\text{m}$.

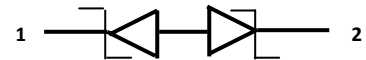
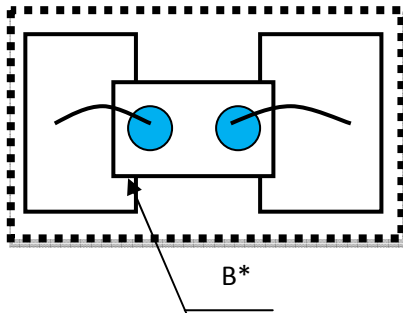
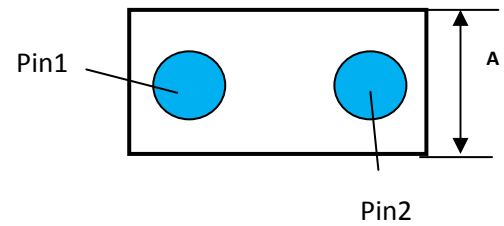
Chip thickness : a) KS-05V2M1A 138+/-12um

Back side: Ti-Ni-Ag;

b) KS-05V2M1B without grinding 470+/-20um

Back side: without metallization.

Top Metal: Al- for wire bonding. Pad Size Pin 1, 2 - $\varnothing 85 \mu\text{m}$.



Bonding diagram in DFN-2L

B* - the thickness of the dielectric between the crystal and the frame should be greater than 10 um

Limiting values

Parameter	Symbol	Conditions	Value	Unit
Working Peak Reverse Voltage	V_{RWM}		5,0.	V
Peak Pulse Power	P_{pp}	$t_p= 8/20\mu\text{s}$	45*	W
Peak Pulse Current	I_{pp}	$t_p= 8/20\mu\text{s}$	3,0*	A
Electrostatic Discharge	V_{ESD}	IEC 61000-4-2, level 4.	+/-8,0 (Contact);	kV
Max.junction temperature	T_j		+150	°C

Characteristics . $T_a=25^\circ\text{C}$.

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_R	Diode reverse leakage current.	$V=\pm 5,0 \text{ V}$	-	-	0,9	μA
V_{BR}	Breakdown voltage.	$I_R=1\text{mA}$	6,4	-	9,0	V
C_j	Diode capacitance. Pin 1 to 2.	$F=1\text{MHz}$, $V_{dc}=0 \text{ V}$.	-	0,35	0,4	pF
V_{CL}	Clamping voltage	$I_{pp}=1,0\text{A}$; $I_{pp}= 3,0\text{A}$; $t_p= 8/20\mu\text{s}$.	-	-	12,0* 15,0*	V

*- For Device testing.